

Sputter-coated TiO₂ films as passivation and hole transfer layers for improved energy conversion with solar fuel WO₃/CuWO₄ photoanodes

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ABSTRACT

Atomic layer deposited (ALD) “leaky” TiO₂ have gained interest as charge-selective protection layers for semiconductor solar fuel electrodes. Here we demonstrate the use of sputter-deposited TiO₂ layers as hole selective contacts for WO₃/CuWO₄ type 2 heterojunction water oxidation photoanodes for the first time. TiO₂ protection layers with varying thicknesses (2 to 128 nm) were deposited using the RF magnetron sputtering technique. The resulting TiO₂ films are amorphous based on Raman spectroscopy and powder XRD. Photoelectrochemical scans and Vibrating Kelvin probe photovoltage spectroscopy show that 2-8 nm TiO₂ layers nearly double the photocurrent to 0.97 mA cm⁻² under AM 1.5 illumination (19% AQE at 350 nm), increase the surface photovoltage signal by 25%, and increase the WO₃/CuWO₄ bandgap. These effects can be attributed to the

selectivity of TiO₂ for photoholes. Additionally, SPV data suggest that TiO₂ overlayers suppress copper-based surface recombination defects. Reduced photocurrent and the photovoltage are seen in thicker TiO₂ films (16 to 128 nm) as a result of an increasing hole transfer resistance and because of light shading effects according to photoaction spectra. The TiO₂ films also improve the stability of the WO₃/CuWO₄ photoelectrodes, allowing nearly constant O₂ evolution over 3 hours after an initial 20-35% loss. Overall, this work establishes RF magnetron sputtering as a useful method to install amorphous TiO₂ passivation layers for improved WO₃/CuWO₄ solar fuel photoelectrodes. Furthermore, we show how the combination of PEC with SPV measurements provides insight into the function of the TiO₂ coatings.

Keywords: Water splitting, RF magnetron sputtering, surface photovoltage spectroscopy, photoelectrochemistry, photoanode, CuWO₄, WO₃, TiO₂.

INTRODUCTION

The water splitting (electrolysis) reaction^{1,2} can generate carbon free fuels from sunlight and water. Photoelectrochemical (PEC) cells enable the process by combining photovoltage generation from a semiconductor with electrochemical water oxidation and reduction. Suitable photoelectrodes are stable against corrosion, have visible light active band gaps, high optical absorption coefficients, long charge carrier lifetime, fast charge transport, and do not utilize rare elements³⁻⁶. Bismuth vanadate fulfills several of these criteria, but its efficiency is constrained by its 2.4 eV band gap, which only allows 12% of the sunlight to be absorbed. CuWO_4 is a potential alternative due to smaller bandgap (2.2-2.4 eV)⁷⁻¹⁰ combined with high stability in aqueous electrolytes^{7,11,12}. Recently, it was shown that the photoanode performance of CuWO_4 can be improved by interfacing the material with WO_3 .¹³⁻¹⁷ The resulting type 2 heterojunction (**Figure 1a**) helps separate charge carriers and prevents them from recombination. $\text{WO}_3/\text{CuWO}_4$ heterojunction films can be made by various methods. Films grown by electrodeposition-annealing have shown to yield a water oxidation photocurrent of 0.80 mA/cm² at 1.23 V vs RHE¹³, and films obtained by spin coating gave 0.5 mA/cm² at 1.23 V vs. RHE and 24% IPCE at 300 nm¹⁸. Sputtered / calcined $\text{WO}_3/\text{CuWO}_4$ films gave 0.35-0.45 mA/cm² at 1.23 V vs. RHE and an IPCE of 35% at 365 nm¹⁶. However, these values are still far away from the theoretical limit of CuWO_4 . This may be attributed to intra-bandgap $\text{Cu}^{2+/+}$ surface states that reduce the carrier mobility and cause electron-hole recombination^{9,10,19-21}. Additionally, these states may lead to Fermi level pinning resulting in a degraded junction and lower photovoltage^{22,23}. These problems can potentially be overcome with TiO_2 overlayers. As was demonstrated recently, TiO_2 films prepared by Atomic Layer Deposition (ALD) can act as “leaky” protection layers^{24,25} by allowing a hole current to pass through it via tunneling mechanism^{2,26}. These layers also protect sensitive main group element

semiconductors from corrosion^{2,24-31}. Accordingly, we speculate that TiO₂ layers can enhance the power conversion of WO₃/CuWO₄ photoanodes for oxygen evolution by forming a hole selective contact, as shown in **Figure 1b**.

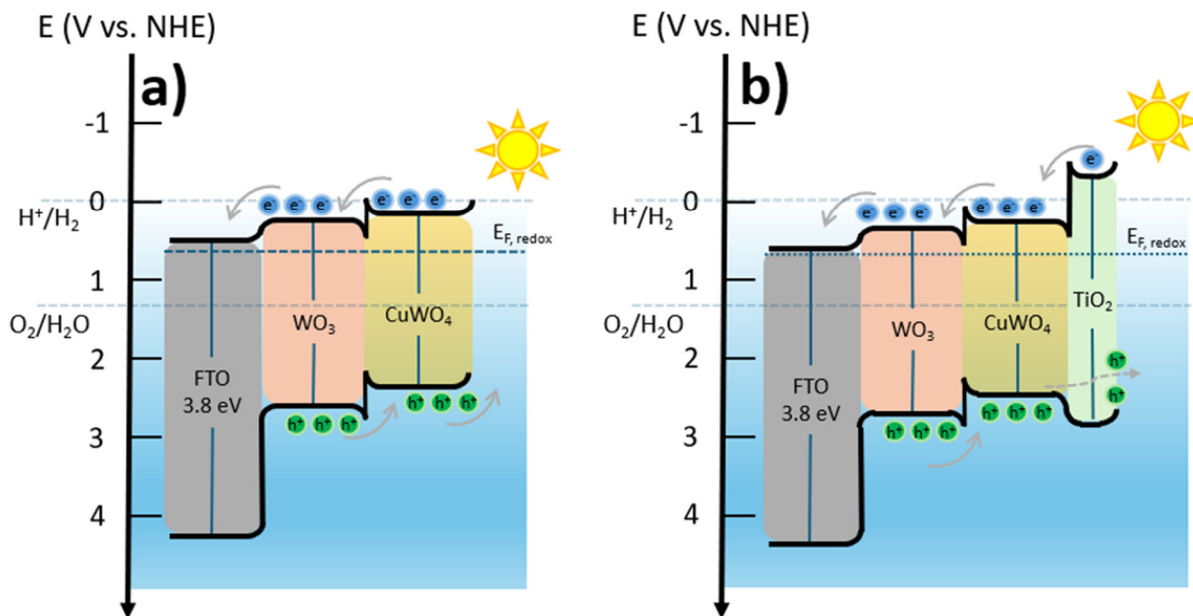


Figure 1. Band energy diagrams for a) FTO/WO₃/CuWO₄ and b) FTO/WO₃/CuWO₄/TiO₂ water oxidation photoanode, incl. depletion layers, Schottky barriers, ohmic back contacts, and charge carrier pathways.

To test this hypothesis, we grew TiO₂ layers onto WO₃/CuWO₄ photoanodes by RF magnetron sputtering deposition, similar to previous reports for Si photocathodes³²⁻³⁵. The resulting photoelectrodes are studied with a combination of X-ray diffraction, Raman spectroscopy, and electron microscopy, and further characterized with surface photovoltage spectroscopy, photoelectrochemical scans, photoaction spectra, and with oxygen evolution measurements. We find that the TiO₂ coatings do enhance the photoelectrochemistry of the

photoanodes by acting as hole selective contacts. However, in thick TiO₂ films these positive impacts are offset by light shading and by larger photohole transport resistance. To balance these influences requires optimization of the layer thickness, as described in the following.

RESULTS AND DISCUSSION

The initial FTO/WO₃/CuWO₄ photoanodes of 1.0 cm² area size were obtained by magnetron co-sputtering from two targets about 10 cm away from the center of the substrate holder. The low-pressure chamber was evacuated and argon and oxygen were injected at 30 sccm and 10 sccm, respectively. A working pressure at 5×10^{-3} torr was used during the deposition, a working temperature of 500°C, and a fixed RF electric power (180 W, 13.6 MHz) and DC power (10W) were applied to the W and Cu targets, respectively, for 2 hours. The sputtered films were then annealed in air (500°C) to convert them into crystalline oxide films. This yields 1 μm thick films containing WO₃ and CuWO₄ phases in 1:1 ratio (submitted for publication). As we reported in the previous work, the activity of these films is enhanced by a type-2 heterojunction that separates photoelectrons towards WO₃ and photoholes towards CuWO₄ (**Figure 1**).

Next, TiO₂ surface layers of variable thickness were deposited by RF magnetron sputtering.³⁶ The depositions were conducted by applying 240 W of power on the RF source (Ti target) while flowing Ar and O₂ gases (flow rates of 40 and 2 sccm, respectively) at a 5×10^{-3} torr working pressure and at 250°C. TiO₂ thickness was controlled via the deposition time (**Table S1**), after previous calibration on a control sample made by 8 h deposition³⁷ (**Figure S1**). The thickness of the control sample was determined as 196 nm using the Cisneros³⁷ method, as described in the supporting information (**Equations S1-4**). Shorter deposition times yield WO₃/CuWO₄/TiO₂ – d

samples where the thickness d is 2 nm, 4 nm, 8 nm, 16 nm, 48 nm, 96 nm, and 128 nm. Powder XRD data of the $\text{WO}_3/\text{CuWO}_4$ samples is summarized in **Figure 2**. Before TiO_2 addition, many of the main diffraction peaks of CuWO_4 (JCPDS 88-0269) are observed, in addition to several WO_3 peaks (JCPDS 71-0305), for example, (0 2 2), (0 -2 2), (2 0 2), (2 2 2), (-1 4 0), and (-1 1 4) and a few FTO diffraction peaks (JCPDS 71-0625). Some peaks from CuWO_4 and WO_3 are found to overlap with each other. For example, the CuWO_4 peaks (1 1 0), (0 -1 1), and (0 1 1) and WO_3 peaks (0 0 2), (0 2 0), and (2 0 0) have the same diffraction angle. Based on a Rietveld refinement ($R_{\text{wp}} = 17.769$), the phase composition of the sample is 61.9% CuWO_4 : 38.1% WO_3 .

Figure 2 also gives the diffraction pattern of a 128 nm TiO_2 reference film grown on a SiO_2 substrate. On the SiO_2 substrate, peaks for rutile and anatase TiO_2 (JCPDS 72-1148 and JCPDS 71-1166, respectively), can be identified clearly. Interestingly, these peaks are completely absent in the $\text{FTO}/\text{CuWO}_4/\text{WO}_3/\text{TiO}_2 - 128$ nm sample. This shows that the TiO_2 film on top of $\text{WO}_3/\text{CuWO}_4$ is amorphous.

In order to further investigate the chemical composition of the films, Raman spectroscopy was employed. Spectra for $\text{SiO}_2/\text{TiO}_2$, $\text{FTO}/\text{WO}_3/\text{CuWO}_4$, and $\text{FTO}/\text{WO}_3/\text{CuWO}_4/\text{TiO}_2 - 128$ nm are summarized in **Figure 3**.

heterostructures are amorphous while similar TiO_2 layers deposited onto SiO_2 are crystalline. The amorphization on $\text{WO}_3/\text{CuWO}_4$ deposited TiO_2 is attributed due to the complex interface between WO_3 and CuWO_4 , which induces localized strain, distortions in the TiO_2 lattice, and structural disorder. Amorphization does not occur on SiO_2 crystals due to the smooth surface which allows the TiO_2 to crystallize more freely.

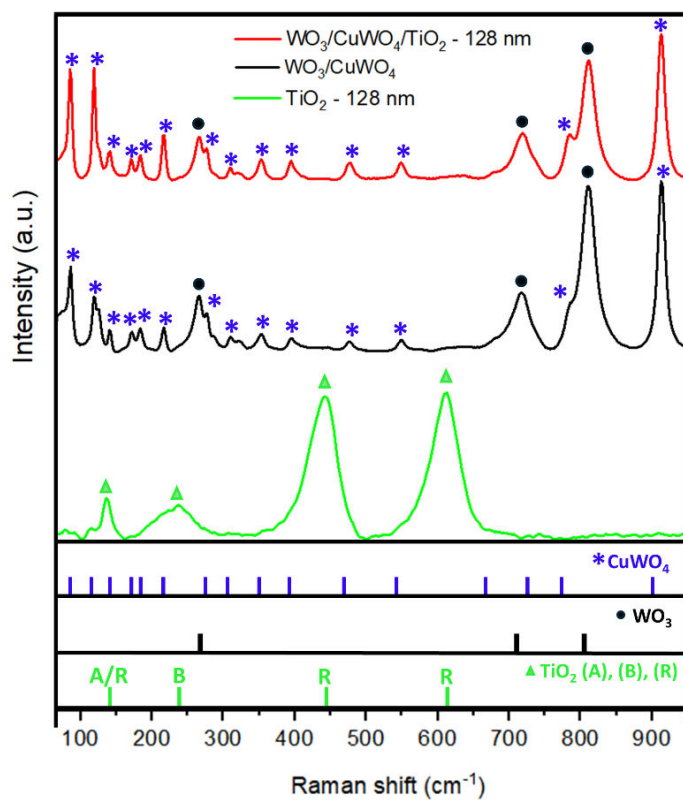


Figure 3. Raman spectra of the samples and the corresponding reference spectra. A, B, and R labels identify Anatase, Brookite, and Rutile vibrational modes, respectively.

To determine the effect of the TiO₂ coating on the sample morphologies and chemical composition, scanning electron microscopy (SEM) measurements coupled with Energy Dispersive Spectroscopy (EDS) were performed. As can be seen in **Figure 4**, the FTO/WO₃/CuWO₄ film contains grains and pores on the 200 - 400 nm scale, without any discernible facets. According to EDS, the film is composed of 64.9 (atom)% of oxygen, 23.3(atom)% of tungsten, and 11.8(atom)% of copper (**Figure S2**). This corresponds to a 60.7: 39.3% ratio of CuWO₄ and WO₃, which is in excellent agreement with the composition suggested by the Rietveld refinement (CuWO₄:WO₃ = 61.9% :38.1%). In comparison, the FTO/WO₃/CuWO₄/TiO₂ – 128 nm sample in **Figure 4b** has an elemental composition of 64.1(atom)% O, 17.9(atom)% W, 9.3(atom)% Ti, and 8.8(atom)% Cu (**Figure S3**) and shows a homogeneous distribution of Ti. This confirms the presence of a conformal TiO₂ overlayer. This overlayer is also responsible for the lower image contrast in the SEM.

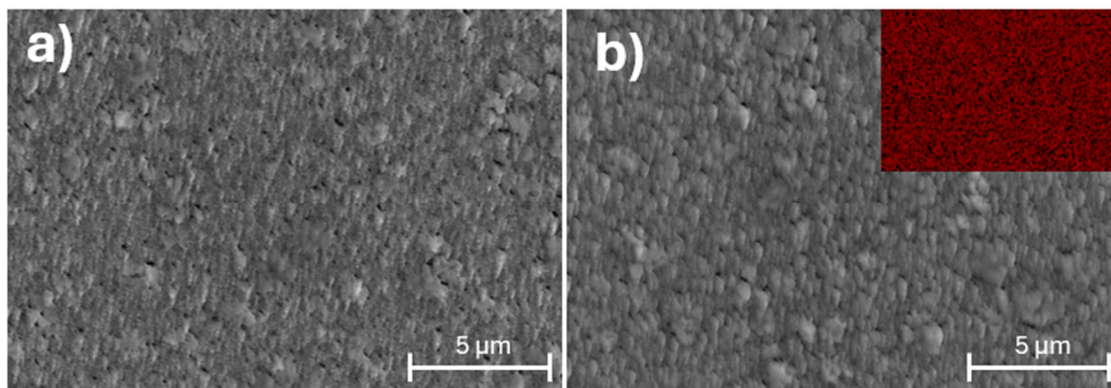


Figure 4. SEM images for a) FTO/WO₃/CuWO₄ and b) FTO/WO₃/CuWO₄/TiO₂ – 128 nm at 10,000x magnification. The insert shows the Ti distribution (red color) from EDS.

Photos of the films are given in **Figure 5**. The yellow appearance is expected for $\text{WO}_3/\text{CuWO}_4$, which absorbs light only in the blue part of the visible spectrum. There are no visible changes resulting from the addition of the TiO_2 .

Diffuse reflectance optical absorbance spectra for all samples are shown in **Figure 6**. The FTO/ $\text{WO}_3/\text{CuWO}_4$ sample has an absorption edge at 531 nm (2.33 eV) near the tabulated band gap of CuWO_4 (2.2-2.4 eV). Addition of thin (2-8 nm) TiO_2 layers moves the absorption edge to slightly higher wavelength (543 nm, 2.28 eV), while thicker TiO_2 films (16-128 nm) diminish the *apparent* absorption below 500 nm. These optical changes arise from interference between light beams reflected at the front and back of the TiO_2 films^{43,44}, which modifies the diffusely reflected signal. These refractive properties^{45,46} are the basis for the thickness determination of the deposited TiO_2 films,³⁷ as shown in **Figures S1 and S4**. However, the interference effect makes it difficult to determine the band gap of the TiO_2 coated films from optical spectra.

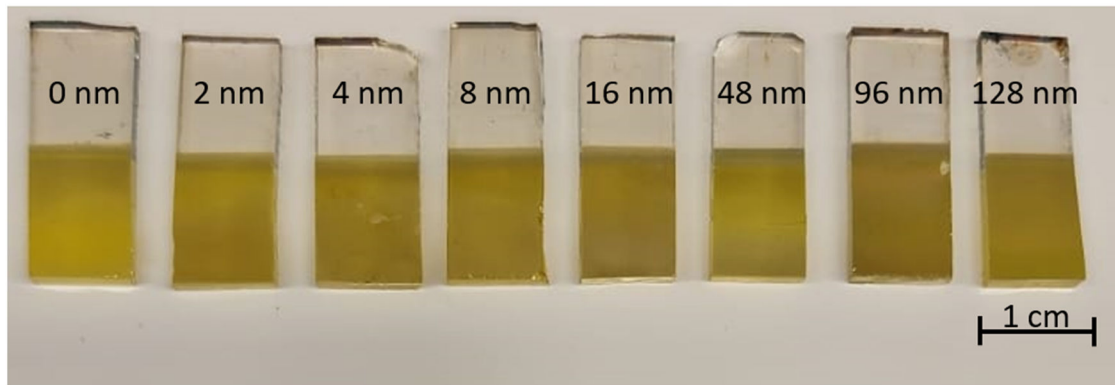


Figure 5. Photos of $\text{WO}_3/\text{CuWO}_4$ films on FTO with variable TiO_2 overlayers (thickness as labelled).

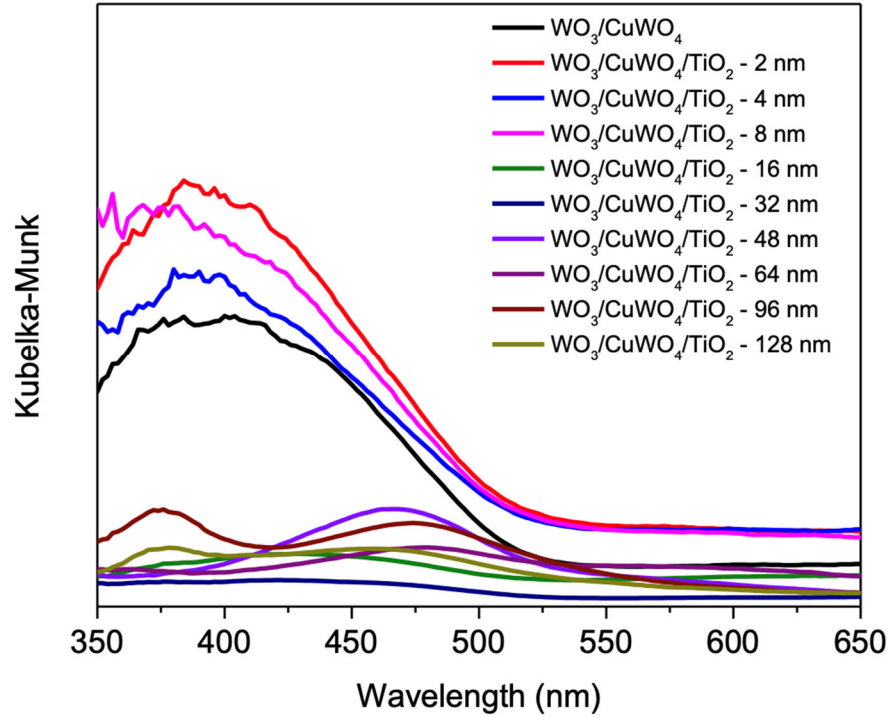


Figure 6. Diffuse Reflectance Optical Spectra for samples shown in **Figure 5**. The absorbance variations at <500 nm are attributed to optical interference effects at the new TiO_2 -air interface^{45,46}. See also **Figures S1 and S4**.

To complement the optical spectra and to observe the contribution of the TiO_2 overlayer to the photovoltage of the $\text{FTO}/\text{WO}_3/\text{CuWO}_4$ samples, vibrating Kelvin probe surface photovoltage spectroscopy (SPS) was employed. In this method, the contact potential difference (CPD) of the sample relative to the gold reference electrode is measured with a semi-transparent gold Kelvin probe⁴⁷. The change CPD in going from dark to illumination defines the surface photovoltage signal, $\text{SPV} = \text{CPD}(\text{light}) - \text{CPD}(\text{dark})$ ⁴⁸⁻⁵⁰. For conductive samples, the SPV equals the photovoltage, i.e. the electric potential difference between majority and minority charge carriers at the interfaces⁵⁰⁻⁵². Spectra for all films are shown in **Figure 7a**.

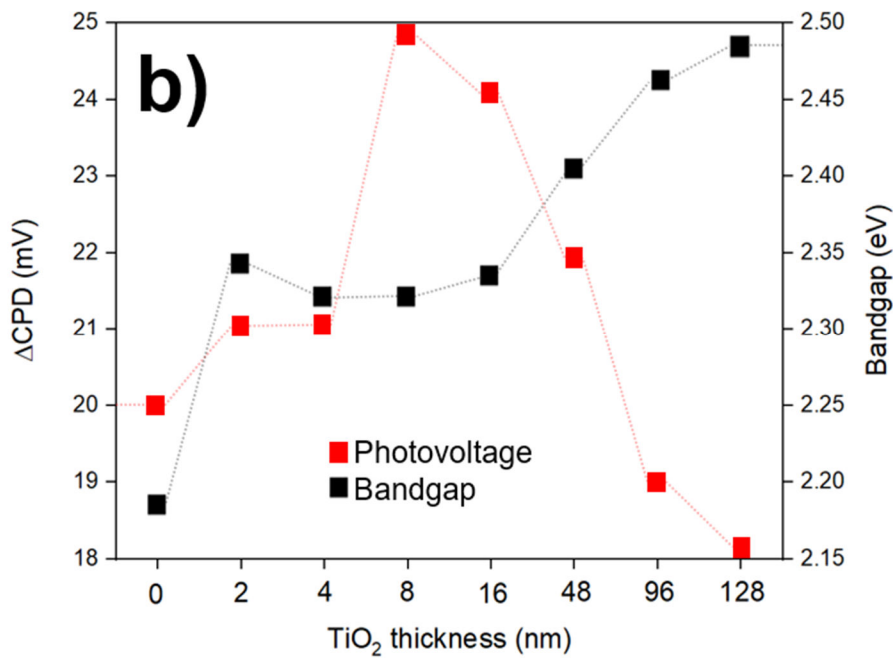
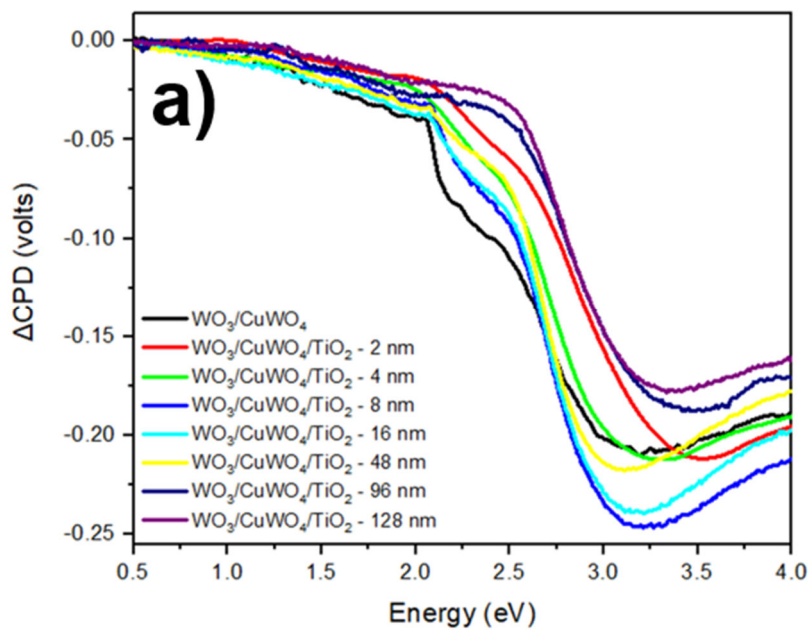


Figure 7. a) Surface Photovoltage Spectroscopy. b) Correlation between TiO₂ thickness and effective SPS bandgap.

All have negative SPV signals, indicative of photoholes moving towards the Kelvin probe as shown in **Figure 8a**. This is typical for n-type semiconductors⁵³, where electrons are repelled by the electric barrier of an electron depletion layer at the surface. Tangential fitting of the major SPV signal to the baseline yields the *effective band gap* of each film. These values are summarized in **Table 1** and plotted in **Figure 7b** together with the maximum SPV signals. The SPV signal shows a volcano-like trend: It increases for thin TiO₂ coatings (2, 4, 8 nm) and then decreases for thicker TiO₂ films. Possible reasons for the SPV decrease are light shading from TiO₂ caused by parasitic absorption and refraction of light,^{43,44} as suggested by the optical spectra in **Figure 6**. Additionally, an increased hole transfer resistance by the thicker TiO₂ films may be responsible for the SPV decrease^{2,24–26}.

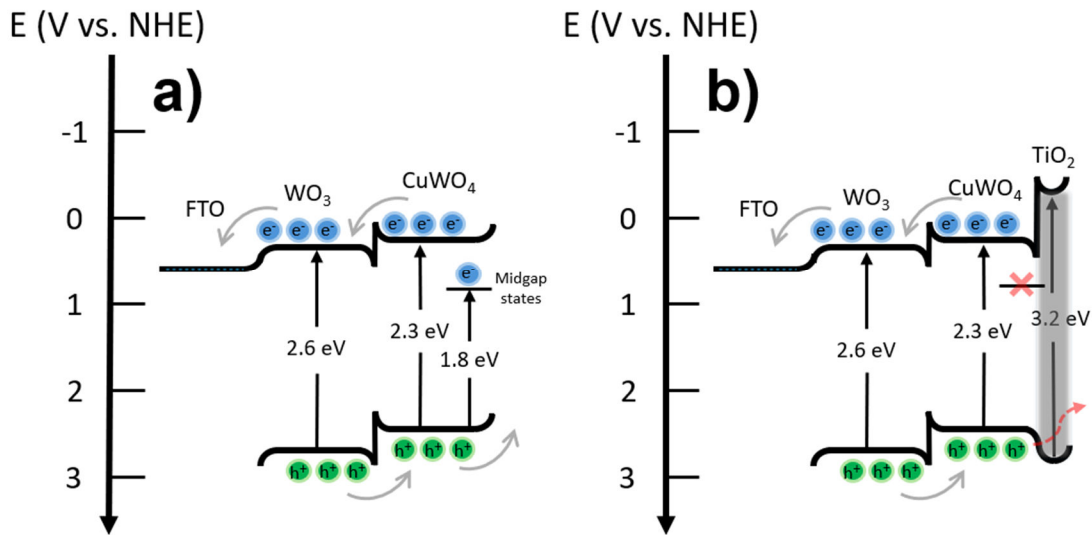


Figure 8. Photochemical charge transfer producing the SPV signal in a) WO₃/CuWO₄, and b) WO₃/CuWO₄/TiO₂ films. In b), the TiO₂ passivating layer removes the mid gap state but also introduces a hole transfer resistance (red arrow).

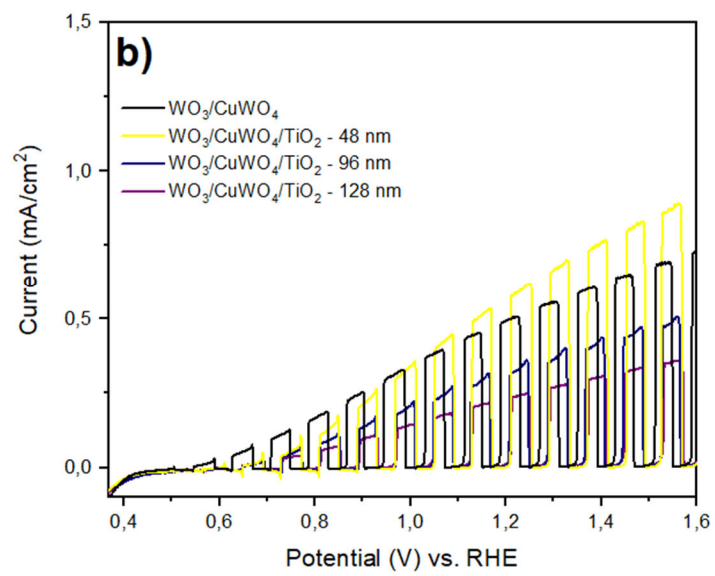
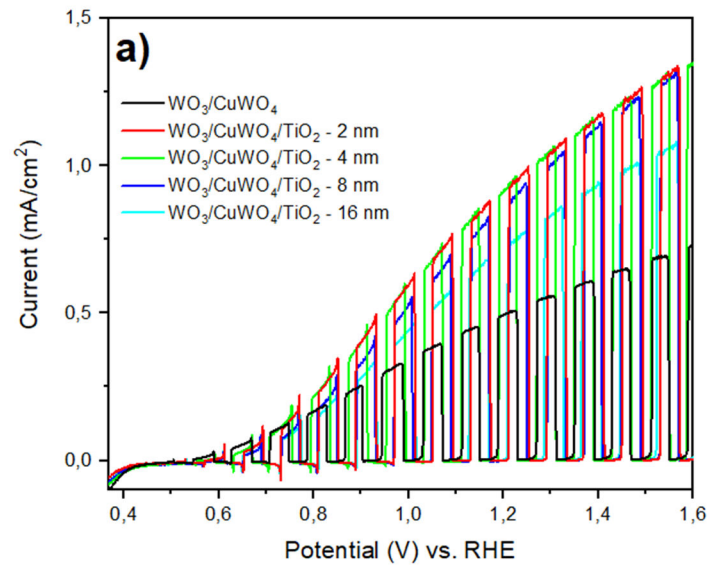
Table 1. Photovoltage, SPS bandgaps, photocurrent, photo-onset, and Faraday efficiency for WO₃/CuWO₄ samples with and without TiO₂.

Sample (TiO₂ thickness /nm)	0	2	4	8	16	48	96	128
ΔCPD (mV)	20	21	21	25	24	22	19	18
Effective Bandgap (eV)	2.18	2.34	2.32	2.32	2.33	2.40	2.46	2.48
Photocurrent (mA/cm²)	0.51	0.96	0.97	0.90	0.75	0.60	0.33	0.24
Photocurrent onset (V vs. RHE)	0.53	0.57	0.57	0.59	0.58	0.61	0.62	0.61
Faraday Efficiency (%)	96	97	98	79	67	73	100	43

As **Figure 7b** shows, effective band gap values increase from 2.18 eV for the non-modified WO₃/CuWO₄ film to 2.48 eV for the sample with the thickest (128 nm) TiO₂ film. The trend has a discontinuity for films with 2 and 4 nm thickness, which have higher than expected effective band gaps. This is attributed to the removal (passivation) of surface defects by the TiO₂ films as shown in **Figure 8a** and **b**. Such defects consisting of Cu^{2+/+} states were previously identified on the basis

of SPV and photoelectrochemistry studies^{10,54}. The $\text{Cu}^{2+/+}$ state is 1.8 eV (690 nm) above the CuWO_4 valence band allowing direct excitation of electrons into it¹⁰. These states are quenched upon coating with 2-8 nm TiO_2 . This raises the photoonset to 2.3 eV, which is identical to our previously reported band gap value for CuWO_4 ¹⁰. Additionally, the effective bandgap increase for the thicker TiO_2 films may result from the increasing photohole transfer resistance of TiO_2 (red arrow in **Figure 8b**). Overcoming this resistance in the thicker films requires photons of progressively higher energy. A similar effect was demonstrated by Tilley's group for ALD grown TiO_2 on a variety of semiconductors²⁵. This hole transfer resistance is also responsible for the reduction of the maximum photovoltage signal in samples coated with >8 nm TiO_2 . Overall, these experiments reveal the passivating and hole transfer limiting effects of TiO_2 coatings on the photovoltaic behavior of the $\text{FTO}/\text{WO}_3/\text{CuWO}_4/\text{TiO}_2$ films.

Next, to determine the ability of the films to convert solar energy into fuel, photoelectrochemical scans under AM 1.5 illumination were recorded in an aqueous phosphate buffer solution at pH 6.5, as shown in **Figure 9**. All samples produce anodic photocurrents that can be attributed to water oxidation and oxygen evolution (see below). The anodic photocurrent begins at potentials of 0.53 V RHE for the $\text{FTO}/\text{WO}_3/\text{CuWO}_4$ electrode and reaches up to 1.0 mA cm^{-2} at 1.23 V RHE for the $\text{FTO}/\text{WO}_3/\text{CuWO}_4/\text{TiO}_2$ - 4 nm sample, almost twice the value of the non- TiO_2 coated sample. The other samples produce intermediate photocurrents (**Table 1** and **Figure 9**), which decrease monotonically with TiO_2 thickness. This trend mimics the photovoltage behavior in **Figure 7b**. It can be attributed to a hole transfer resistance of the TiO_2 coating. This explains the photocurrent decay seen in **Figure 9c**.



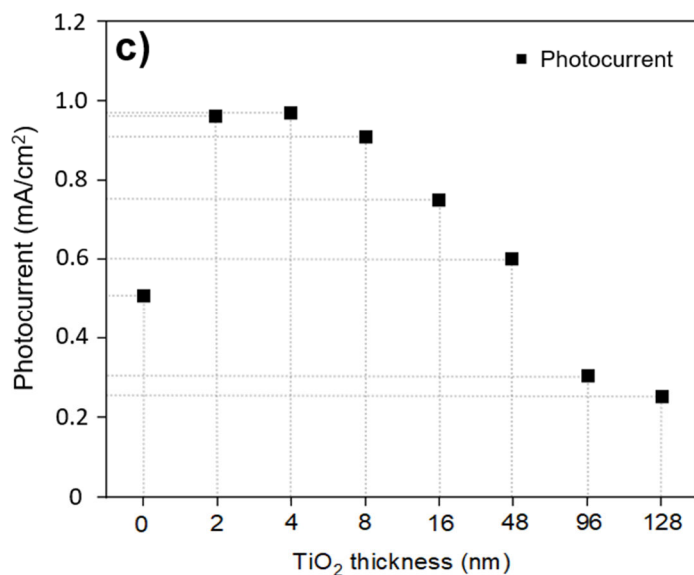
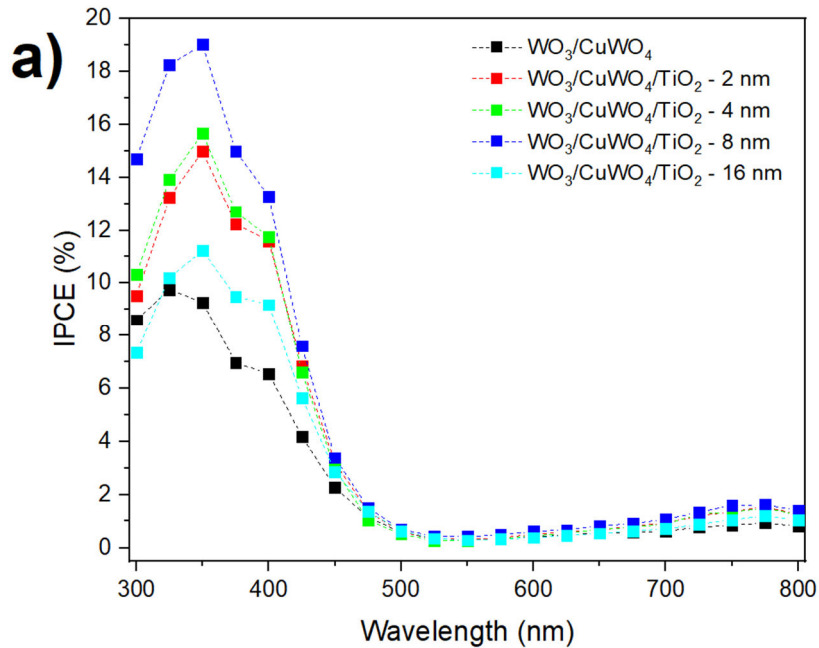


Figure 9. Linear sweep voltammograms in a 0.1 M phosphate buffer solution at pH 6.5 under AM 1.5 G irradiation from a 300 W xenon arc lamp. (a) WO₃/CuWO₄, WO₃/CuWO₄/TiO₂ – 2 -16 nm, (b) for WO₃/CuWO₄, WO₃/CuWO₄/TiO₂ – 48 - 128 nm. (c) Photocurrent (1.23 V RHE) comparison.

Additionally, the TiO₂ layer causes small change in the photocurrent onset potential (photovoltage). While FTO/WO₃/CuWO₄ has an onset of 0.53 V vs. RHE (**Figure 9a**), corresponding to a photovoltage of 1.23 V - 0.53 V = 0.70 V, samples with added TiO₂ have onsets between 0.57 and 0.62 V vs. RHE, and correspondingly lower photovoltage. The photovoltage loss increases with TiO₂ thickness, and therefore is ascribed to the hole transfer resistance of TiO₂. As holes accumulate near the CuWO₄/TiO₂ interface, the positive charge moves the WO₃/CuWO₄ Fermi levels to more oxidizing values.

To complement the SPS and photoelectrochemical scans, photoaction spectra were recorded for all samples (**Figure 10**). As expected, incident photon to current conversion efficiency (IPCE) values vary strongly with photon energy. Non-zero IPCE values are observed at photon

energies above the band gap of $\text{CuWO}_4/\text{WO}_3$. The highest IPCE occurs at 350 nm for samples with 2 – 16 nm TiO_2 (**Figure 10a**), and at 400 nm for samples with 48 - 128 nm TiO_2 overlayers. Below 400 nm, IPCE values decline sharply. This is due to the shorter light penetration depth at these wavelength. Because excitation only occurs in the front 100~150 nm of each sample, electron transport to the back electrode becomes a limiting factor. Samples coated with 48 - 128 nm TiO_2 experience shading from parasitic light absorption from TiO_2 (E_G 3.0 eV). This explains the lower 350 nm IPCE values for these samples. Additionally, the data shows that samples coated with 2-16 nm TiO_2 layers have 50% higher IPCE values (15.0%, 15.7%, 19.0%, and 11.3%, respectively at 350 nm) than the bare $\text{FTO}/\text{CuWO}_4/\text{WO}_3$ sample (9.3%). This agrees with the SPV and photoelectrochemistry data above. It reflects the suppression of the Cu^{2+} recombination by thin TiO_2 layers and the insulating effect of thick TiO_2 overlayers on photohole transport to the electrolyte. These two opposing influences are best balanced for the 8 nm TiO_2 overlayer, allowing the highest IPCE in that case (**Figure 10c**).



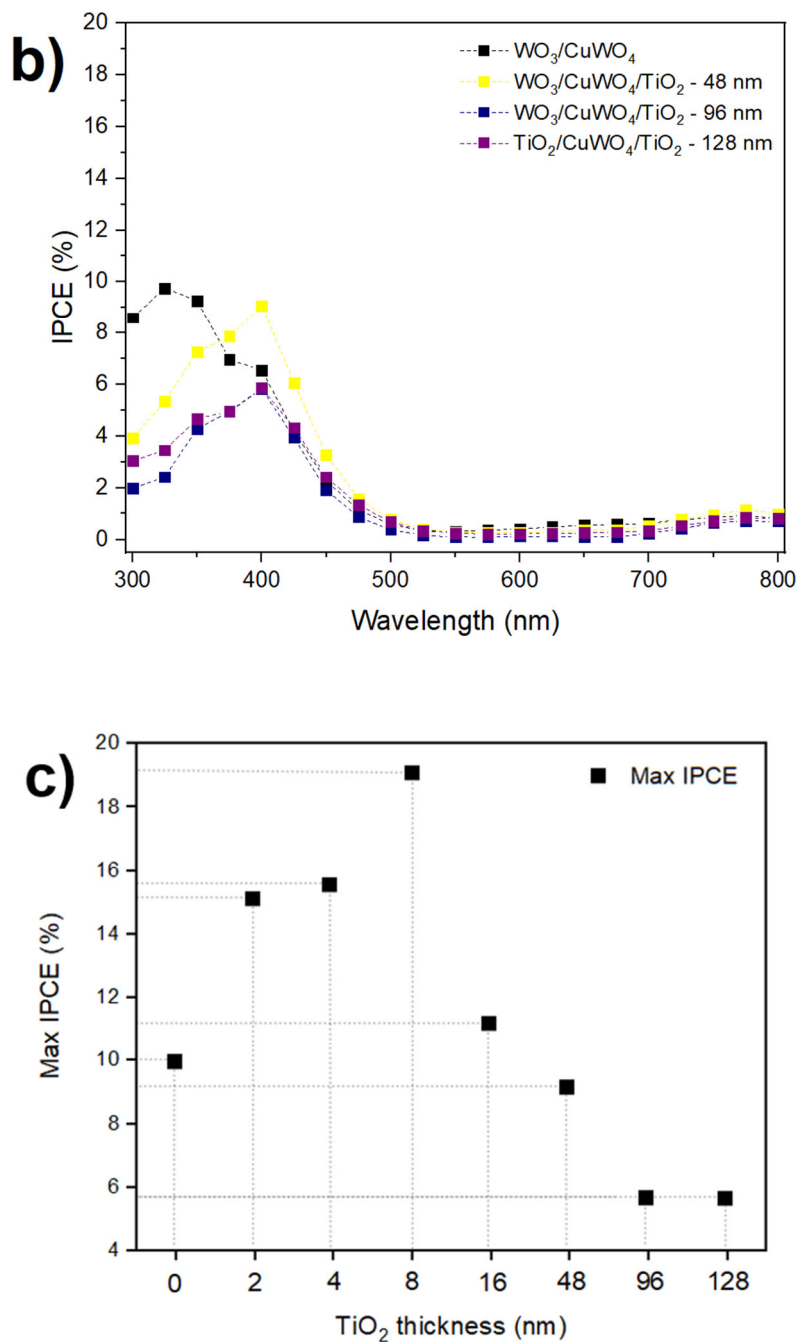


Figure 10. Photoaction spectra for WO₃/CuWO₄/TiO₂ electrodes in 0.1 M phosphate buffer solution at pH 6.5. a) Samples with 0, 2, 4, 8, and 16 nm of TiO₂. b) Samples with 48, 96, and 128 nm of TiO₂. c) Comparison of max IPCE values. Non-zero IPCE values at $\lambda > 550$ nm are a measurement artefact resulting from second order diffraction at the monochromator optical grating. See optical emission spectra in **Figure S5**.

Lastly, chronoamperometry and Faraday efficiency measurements were performed to assess the stability of the samples and their ability to generate O₂. According to **Figure 11** almost all samples loose 20-35% of their photocurrent in the first 20 mins under ~ 5 suns illumination, but then remain relatively stable (~90% of current maintained) for 180 minutes. Based on the literature, WO₃/CuWO₄ electrodes are regarded stable under 1 sun illumination in neutral aqueous solutions^{12,17,55}. Stability is maintained with the TiO₂ coatings and improved for WO₃/CuWO₄/TiO₂ – 8, 16, 48 nm.

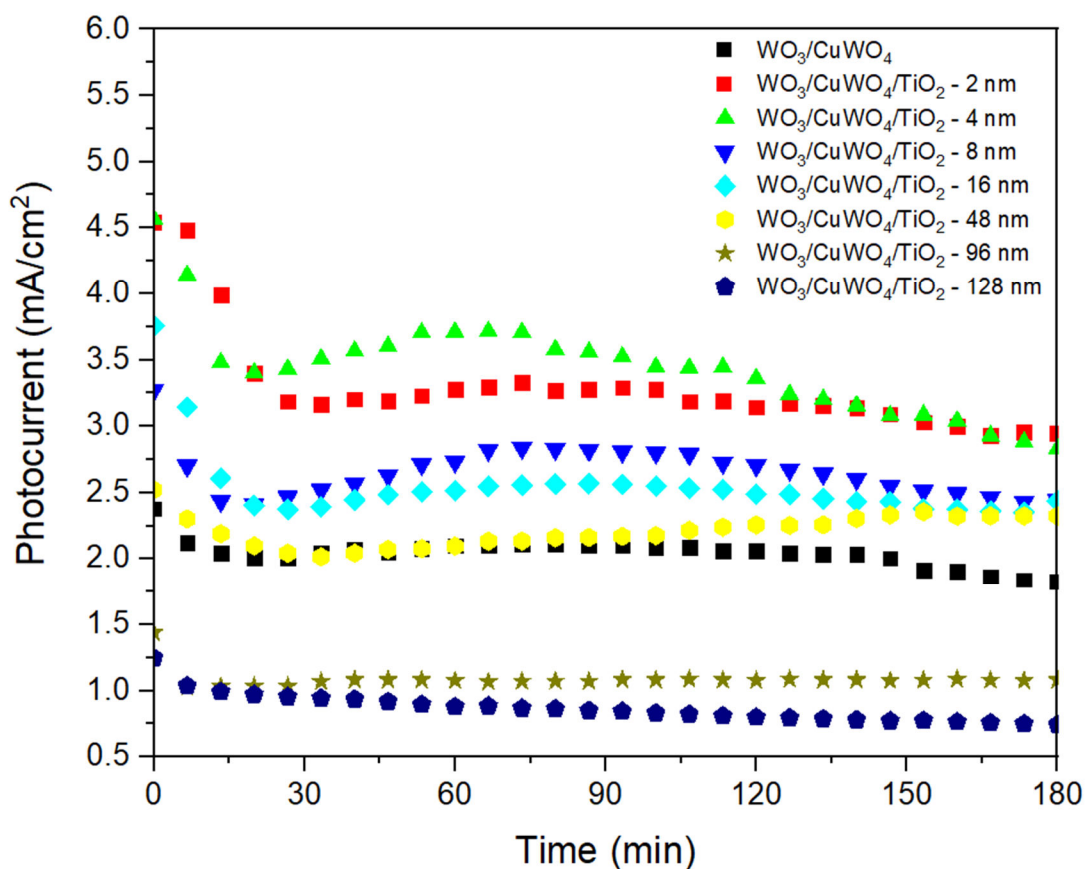


Figure 11. Photocurrent at 1.23 V vs. RHE in 0.1 M phosphate buffer solution at pH 6.5 under 464-496 mW cm⁻² illumination from a 300 W xenon arc lamp. The higher light intensity was chosen to specifically probe the aging of the electrodes.

Figure 12 shows O₂ generated with each photoelectrode over the 3 h illumination experiment. Oxygen concentrations rise nearly linearly, with rates determined by the photocurrent of each electrode. Calculated Faraday efficiencies are presented in **Table 1**. Near unity values are seen for WO₃/CuWO₄/TiO₂ – 0, 2, and 4 nm, while values near 75% occur for films with thicker TiO₂ films. This suggests that other oxidation processes are contributing to the photocurrent in these cases. Indeed, TiO₂ photoanodes have been reported to generate H₂O₂ in addition to O₂^{56–58}. However, a preliminary analysis via iodometry (oxidation of potassium iodide) did not detect any H₂O₂. Further studies are needed to determine the cause of the lower Faraday efficiency.

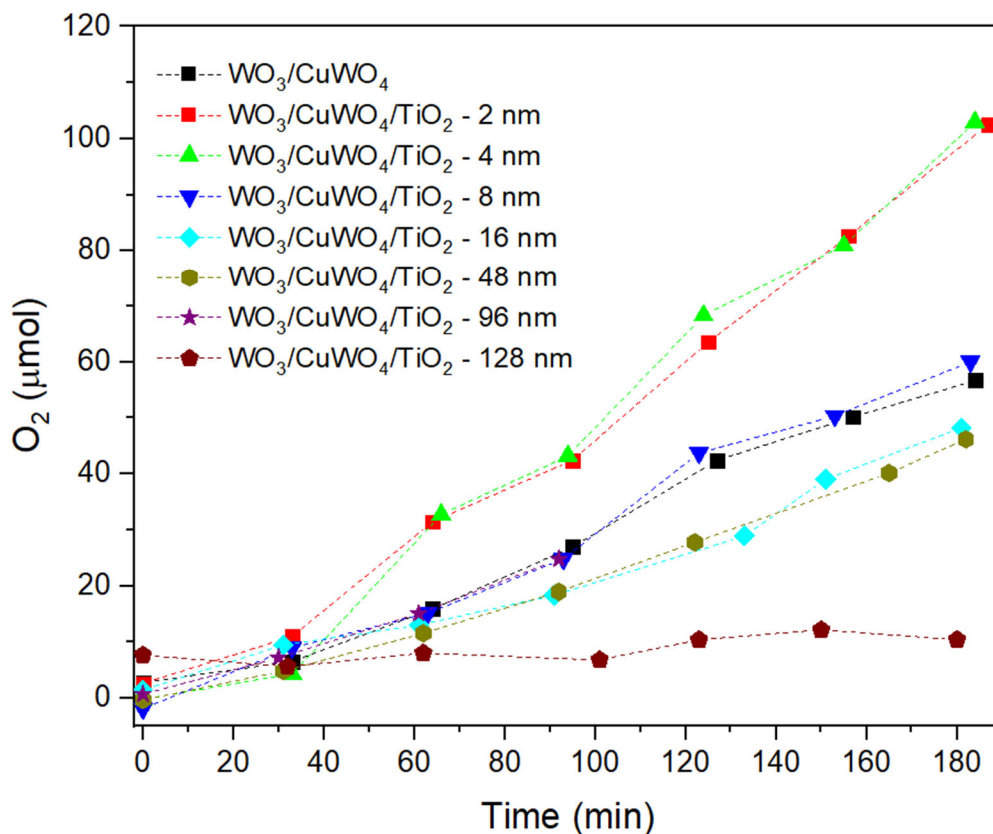


Figure 12. Oxygen evolution for WO₃/CuWO₄ and WO₃/CuWO₄/TiO₂ electrodes at 1.23 V vs RHE in 0.1 M phosphate buffer solution at pH 6.5 under ~500 mWcm⁻² illumination from a 300 W xenon arc lamp.

CONCLUSIONS

FTO/WO₃/CuWO₄/TiO₂ electrodes with enhanced photoelectrochemical water oxidation properties were achieved by the addition of sputtered TiO₂ overlayers for the first time. According to XRD diffraction, Raman spectroscopy, and SEM / EDS measurements, the TiO₂ overlayers are amorphous and have thickness between 2 and 128 nm. Thin (2 - 8 nm) TiO₂ layers increase the photocurrent and the photovoltage, according to photoelectrochemical scans and vibrating Kelvin probe surface photovoltage spectroscopy. This is attributed to improved charge separation at the TiO₂ hole selective contact. Additionally, SPV data suggests that TiO₂ passivates WO₃/CuWO₄ surface defects and increases the effective band gap of the WO₃/CuWO₄ composite. With thicker TiO₂ coatings (16 – 128 nm) these benefits are offset by an increased hole transfer resistance and a shading effect from TiO₂. TiO₂ coatings also mildly increase the stability of the WO₃/CuWO₄ photoelectrodes during 3 hour experiments under 5 sun illumination, but result in lower O₂ evolution Faraday efficiencies, for reasons not entirely clear. Overall, this work establishes sputter coating of amorphous TiO₂ as a method to enhance the water oxidation performance of WO₃/CuWO₄ solar fuel photoelectrodes. We expect that these results can be applied to other metal oxide photoanodes.

EXPERIMENTAL

Synthesis. Reactive RF and DC magnetron sputtering was performed in a commercial Kurt J. Lesker reactor using Macashew Tungsten (99,999%) and Kurt J. Lesker copper (99.99%) targets. WO₃/CuWO₄ films were first deposited onto FTO/glass substrates from MSE supplies (15 Ω/sq), as described in our previous publication (submitted for publication). TiO₂ depositions were conducted by applying 240 W RF power on the Ti target while flowing Ar and O₂ gases at flow rates of 40 and 2 sccm, respectively, and using 5 × 10⁻³ torr total pressure. The temperature during the deposition was controlled by a Neocera heater/controller adjusted to 250°C. The real temperature measured by an attached thin chromel-alumel thermocouple was 150 ± 20°C. The difference is due to heat losses in the heater-substrate interface and the chamber walls which remain at room temperature.

Characterization. The structural properties of the films were analyzed by X-ray diffractometry in a Rigaku D-Max – 2100/PC equipment, with Cu Kα (1.54056 Å) radiation, and using a Bruker D8 Advance Eco with Cu Kα and a monochromatic wavelength of 1.5418Å, using 2θ configuration, 15-60° range, and a step size of 0.01°. Raman spectroscopy (Horiba-Evolution) analysis was performed in a spectral resolution lower than 1 cm⁻¹ with a 532 nm laser to evaluate the vibrational modes of the samples. The morphology of the samples was observed with an FEI Scios Dual Beam FIB/SEM microscope (scanning electron microscopy) with Oxford X-Max Energy Dispersive X-ray Spectroscopy (EDS) Detector and accelerating voltage of 10-20 KV. The optical properties of the samples were verified with measurements on a Perkin Elmer *Lambda 1050* UV/Vis/Nir spectrophotometer (data interval of 1.00 nm) at a scan speed of 141 nm/min. Surface photovoltage spectroscopy was performed in air environment utilizing a semi-transparent vibrating gold-mesh

Kelvin probe (Delta PHI Besocke) controlled by a Kelvin Control 7 Oscillator/amplifier (Besocke Delta Phi). Samples were illuminated through the Kelvin probe with monochromatic light in the 3390–40,000 cm^{-1} range generated by an Oriel Cornerstone 130 monochromator powered by a 300 W Xe arc lamp source. The light intensity at the sample was 50-150 $\mu\text{W}/\text{cm}^2$. Spectra were acquired by stepping the photon energy by 0.0124 eV every 5 seconds and by measuring the contact potential difference (CPD) value at each step. The SPV signal was obtained according to $\text{SPV}=\text{CPD}(\text{light})-\text{CPD}(\text{dark})$. Before each scan, a stable CPD baseline was first established.

Electrochemical characterizations were performed using a Gamry Reference 600 Potentiostat linked to a photoelectrochemical cell (PEC), filled with 50 mL of 0.1 M $\text{Na}_2\text{HPO}_4/\text{NaH}_2\text{PO}_4$ buffer solution at pH 6.5, and containing a Pt counter electrode and a saturated calomel reference electrode separated by a KCl salt bridge. The cell was open to air and constantly stirred at 300 rpm. Chopped light linear sweep voltammetry measurements were performed under AM 1.5 G irradiation from a 300 W xenon lamp source. The irradiance at the electrode was 100 mW cm^{-2} , as determined by calibration with via commercial silicon solar cell. The system was also calibrated using the redox potential $\text{K}_4[\text{Fe}(\text{CN})_6]$ at 0.358 V (NHE). IPCE measurements were performed at 1.23 V vs RHE using light from an Instruments SA, Inc. H10 1200 (350-800 nm) monochromator behind a 300 W Xenon lamp. The wavelength was reduced in 25 nm increments beginning at 875 nm. The irradiance at each wavelength was measured using a NIST Traceable radiometer/photometer from *International Light*, and the IPCE values were calculated using equation 1 below. Here, j_{ph} is the photocurrent density in mA/cm^2 at 1.23 V RHE, h is the Planck's constant ($6.62 \times 10^{-34} \text{ J}\cdot\text{s}$), c is the speed of light ($3.0 \times 10^8 \text{ m/s}$), e is the charge of a single electron ($1.6 \times 10^{-19} \text{ C}$), P_{mono} is the power density of monochromatic light in $\text{mW}\cdot\text{cm}^2$, and λ is the monochromatic wavelength of light in nm.

$$IPCE = \frac{j_{ph} \times \frac{hc}{e}}{P_{mono} \times \lambda} \times 100\% \quad (1)$$

For Faraday efficiency measurements, two salt bridges were used (one of them containing the Pt counterelectrode open to air). The cell was sealed to avoid air contamination, and the cell was purged with argon for 20 min prior to the experiment. Chronoamperometry was performed at 1.23 V vs RHE for 180 minutes. 50 μ L of gas was collected from inside of the cell every 30 min and injected into a Varian CP-3800 gas chromatograph to measure the amount of oxygen. Equation 2 was used to calculate the theoretical amount of oxygen. Here, Q is the charge in Coulomb ($\int_0^t Idt$), n is the number of electrons, and F is the Faraday constant 96,485 C/mol.

$$O_2, \text{ theory} = \frac{Q}{n.F} = \frac{\int_0^t Idt}{4.96485} \quad (2)$$

ACKNOWLEDGMENT

The authors thank the Fundação de Amparo à Pesquisa do Estado de São Paulo – FAPESP for financial support via grants 2022/06542-9 and 2023/04793-7. Surface photovoltage and photoelectrochemical measurements were supported by a grant from the U.S. Department of Energy, Office of Science, Office of Basic Energy Sciences under Award Number DOE-SC0015329.

SUPPORTING INFORMATION

Additional experimental details, transmittance and absorbance data, film thickness data, EDS maps and spectra, and light emission spectra.

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